

<b>Notice of References Cited</b>	Application/Control No. 10/585,407		Applicant(s)/Patent Under Reexamination NAKATA, TSUNEO	
	Examiner Andrew Lee		Art Unit 2472	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,247,464	09-1993	Curtis, Robert A.	379/25
*	B	US-2003/0154301	08-2003	McEachern et al.	709/237
*	C	US-2004/0233931	11-2004	Cohen, Ron	370/468
*	D	US-2004/0203827	10-2004	Heiner et al.	455/452.1
*	E	US-2005/0100035	05-2005	Chiou et al.	370/412
*	F	US-2009/0086628	04-2009	Gracon et al.	370/230
*	G	US-2005/0132062	06-2005	Halme, Matti	709/227
*	H	US-2002/0101919	08-2002	Takada et al.	375/225
*	I	US-7,568,045	07-2009	Agrawal, Sanjay K.	709/233
*	J	US-7,180,858	02-2007	Roy et al.	370/232
*	K	US-7,099,284	08-2006	Halme, Matti	370/253
*	L	US-6,430,160	08-2002	Smith et al.	370/252
*	M	US-6,075,769	06-2000	Ghanwani et al.	370/229

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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